

Contents

1	Introduction	1
1.1	Layered Magnetic Structures	1
1.1.1	Magnetoresistive Devices	1
1.1.2	Spintronics	5
1.1.3	Ferromagnetic–Antiferromagnetic Heterostructures	6
1.1.4	Need for Layer-Resolved Information	8
1.1.5	Need for Time Resolution	9
1.2	Approaches to Layer-Resolved Magnetic Imaging	13
1.2.1	Interference-Based Approach	13
1.2.2	Electronic Properties-Based Approach	15
2	Magneto-Optical Effects	19
2.1	Overview	19
2.2	Optical Basics of Conventional Effects	23
2.2.1	Wave Equation	23
2.2.2	Polarized Light	30
2.2.3	Birefringence, Dichroism, and Optical Activity	36
2.2.4	The Compensator	40
2.2.5	Reflection and Transmission of Polarized Light	44
2.3	Electromagnetic Basics of Conventional Effects	49
2.3.1	The Dielectric Permittivity Tensor	49
2.3.2	Solutions	50
2.4	Faraday and Kerr Effect	54
2.4.1	Phenomenological Description	54
2.4.2	Geometry of the Rotation Effects	63
2.4.3	Kerr Contrast and Signal	68
2.4.4	Microscopic Origin of the Kerr Effect	73
2.5	Voigt Effect	75
2.6	Gradient Effect	81

2.7	X-Ray Magnetic Dichroism.	86
2.7.1	X-Ray Magnetic Linear Dichroism	86
2.7.2	Circularly Polarized X-rays.	91
2.7.3	X-Ray Magnetic Circular Dichroism	92
3	Depth-Sensitive Conventional Magneto-Optical Microscopy	97
3.1	Magneto-Optical Microscopy and Magnetometry	97
3.1.1	Wide-Field Microscopy	98
3.1.2	Laser-Scanning Microscopy	103
3.1.3	Magneto-Optical Magnetometry and Ellipsometry	105
3.2	Depth Sensitivity of Conventional Magneto-Optics.	107
3.2.1	Experimental Proof of Depth Sensitivity.	108
3.2.2	Theoretical Approaches to Depth Sensitivity in Magneto-Optics.	109
3.2.3	Depth Sensitivity Function	115
3.2.4	Depth Sensitivity in Magnetic Films	119
3.2.5	Depth Sensitivity in Magnetic Multilayers	124
3.2.6	Depth Selectivity in Magnetic Multilayers	127
3.3	Depth-Selective Kerr Microscopy.	130
3.4	Voigt- and Gradient Microscopy	137
4	Depth-Sensitive Photoelectron Emission Microscopy.	141
4.1	Photoelectron Emission Microscopy	141
4.2	Electron Yield Detection of Absorption from Buried Layers	142
4.3	Imaging Ferromagnetic Materials by X-ray Magnetic Circular Dichroism.	150
4.3.1	NiFe/Cu/Co Trilayers.	151
4.3.2	Co/Cu/Ni Trilayers	153
4.3.3	NiFe/Al ₂ O ₃ /Co Trilayers	161
4.3.4	Ni/Fe/Co Trilayers.	163
4.3.5	Ni/FeMn/Co Trilayers	166
4.4	Imaging Antiferromagnetic Materials by X-ray Magnetic Linear Dichroism.	169
4.4.1	Magnetic Linear Dichroism as Contrast Mechanism for Layer-Resolved Magnetic Imaging Using PEEM.	170
4.4.2	Exchange Coupling at the Interface of NiO and a Ferromagnetic Metal	172
4.4.3	CoO/NiO Heterostructures	176
4.4.4	Co/LaFeO ₃ Heterostructures	178
4.5	Time- and Layer-Resolved Magnetic Imaging by XMCD-PEEM	180

5	Magnetic Transmission Soft X-Ray Microscopy	189
5.1	Introduction	189
5.2	Absorption of X Rays in Transmission Experiments.	190
5.3	Basic Elements in Magnetic Transmission Soft X-Ray Microscopy.	197
5.3.1	Fresnel Zone Plates as Optical Elements.	197
5.3.2	Experimental Set-Up	199
5.3.3	Sample Properties	202
5.3.4	Sensitivity to Thin Layers	203
5.4	Imaging Layered Magnetic Microstructures	204
5.4.1	Elemental Specificity	204
5.4.2	Magnetization Reversal Processes in Nanostructured Elements	205
5.4.3	Domain Structures in Multilayered Systems	210
5.5	Time and Layer-Resolved Magnetic Imaging by M-TXM.	216
5.6	Future Perspectives	220
	References.	221
	Index	241

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